SN54259, SN54LS259B, SN74LS259B 8-BIT APN74259, SN74LS259B)DRESSABLE LATCHES

SDLS086

DECEMI

3ER 1983 - REVISED MARCH 1988

 8-Bit Parallel-Out Storage Register Performs Serial-to-Parallel Conversion with Storage

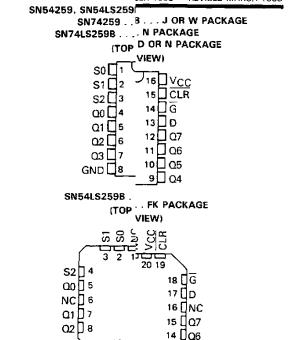
- · Asynchronous Parallel Clear
- · Active High Decoder
- Enable/Disable Input Simplified Expansion
- Expandable for N-Bit Applications
- Four District Functional Modes
- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These 8-bit addressable latches are designed for general purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and active-high decoders or demultiplexers. They are multifunctional devices capable of storing single-line data in eight addressable latches, and being a 1-of-8 decoder or demultiplexer with active-high outputs.

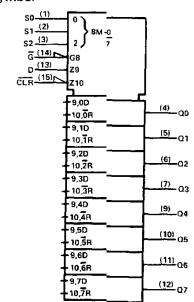
Four distinct modes of operation are selectable by controlling the clear (CLR) and enable (G) inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in terminal is written into the addressed latch. The addressed latch will follow the data input with all unaddressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latches, enable G should be held high (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode, the addressed output will follow the level of the D input with all other outputs low. In the clear mode, all outputs are low and unaffected by the address and data inputs.

The SN54259 and SN54LS259B are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74259 and SN74LS259B are characterized for operation from 0°C to 70°C.



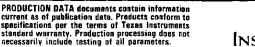
NC - No internal con

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.





SN54259, SN54LS259B, SN74259, SN74LS259B 8-BIT ADDRESSABLE LATCHES

FUNCTION TABLE

INPUT	re	OUTPUT OF	EACH	
CLR	_	ADDRESSED	OTHER	FUNCTION
CLH	G	LATCH	ООТРОТ	
н	L	D	Q _{iO}	Addressable Latch
н	Н	a_{i0}	Q _{iO}	Memory
L	L	D	L	8-Line Demultiplexer
L	н	L	L	Clear

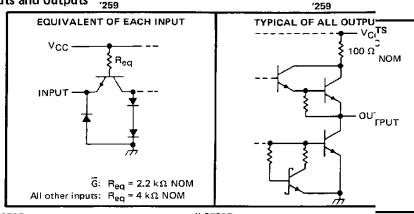
 $H \equiv high\ level,\ L \equiv low\ level$

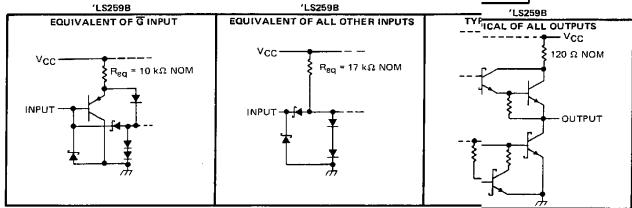
LATCH SELF

ECTION TABLE

SE	LECTI	NPU'	
S2	S1	srs	LATCH
-	L	LD	ADDRESSED
٦	L	н_	0
ا ا	Н	1	1
_	Н	Н	2
L			3
Н	L	L	4
Н	L	н	5
H	н	Ĺ	6
Н	Н	Н	_
L			7

schematic of inputs and outputs 7259





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Input voltage: SN54259, SN74259.	5.5 V
SN54LS259B, SN74L	.\$259B
Operating free-air temperature range:	SN54259, SN54LS259B – 55°C to 125°C
	SN74259, SN74LS259B 0°C to 70°C
Storage temperature range	– 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal,

 $[\]mathbf{D} \equiv \mathbf{the} \ \mathbf{level} \ \mathbf{at} \ \mathbf{the} \ \mathbf{data} \ \mathbf{input}$

 $[\]alpha_{i0} \equiv \text{the level of } \alpha_i \ (i=0,1,\dots,7, \text{ as appropriate}) \ \text{before the indicated steady-state input conditions were established.}$

recommended operating conditions

		SN54259		_			
		MIN NOM MA	SN74259		UNIT		
Supply voltage, VCC				AIN I	MON	MAX	UNIT
High-level output current, IOH		-8	4 ق	.75	5	5.25	٧
Low-level output current, IOL			16			800	μА
Width of clear or enable pulse,	t _W	15	~ <u>`</u>			16	mA
0	Data	15		15			ns
Setup time, t _{su}	Address	5↑		151			пs
44-14	Data	01		5↑			''3
Hold time, th	Address	20↑		<u>0</u> †			ns
Operating free-air temperature,	ΤΔ	-55 1:	25	201			113
			≕	0		70	°C

[†]The arrow indicates that the rising edge of the enable pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (ur nless otherwise noted)

PARAMETER		TEST CO	TEST CONDITIONS†		SN54259 -			SN74259					
		<u> </u>		MIN	TYP‡	MAX-	MIN	TYP‡		דומט 🕂			
VIH.	High-level input volta	ge			2		-		1174	WIAA	+		
VIL	Low-level input voltage	je			1		0.8	2			<u> </u>		
VIK	Input clamp voltage		VCC = MIN,	I ₁ = 12 mA			-1.5			8,0	<u> </u>		
			V _{CC} = MIN,	V _{IH} = 2 V,						-1.5	V		
∨он	High-level output volt	age	V _{IL} = 0.8 V,	I _{OH} = -800 μA	2.4	3.4		2,4	3.4		V		
· · ·			V _{CC} = MIN,	V _{IH} = 2 V,							ļ		
VOL Low-level output volt		age	VIL = 0.8 V,	IOL = 16 mA	0.2	0.4		0.2	0.4	v			
11	Input current at maximum input voltage		V _{CC} = MAX,	V ₁ = 5.5 V			1-	ļ		1	 		
	High-level input	Ğ					80-				mA		
ΙΗ	current	Other inputs	V _{CC} = MAX,	V ₁ = 2.4 V				40				80	ДЩ
	Low-level input	Ğ			 		-3.2			40			
¹ L	current	Other inputs	V _{CC} = MAX,	$V_1 = 0.4 V$		ļ				-3.2	mA		
	Short-circuit output current§		1.		l		<u>-1,6</u>			-1.6	1112		
los		ritenta	V _{CC} = MAX		-18		<u>–57</u>	-18		-57	mA		
lcc_	Supply current		V _{CC} = MAX,	See Note 2	L	60	90-		60	90	mA		

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conclitions.

switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
^t PHL	CLR	Any O			16	25	ns			
[†] PLH	Data	Any Q	CL = 15 pF,	Τ' Τ		14	24	-		
[†] PHL	Data	Ally Q			11	20	— пѕ			
tPLH .	*****	Address Any Q	00	Anv. 0		R _L = 400 Ω,		15	28	-
tPHL .	Address		See Note 3		17	28	ns			
^t PLH		1-110	4 }		12	20				
[†] PHL	Ġ	Any Q			11	20	ns			

 t_{PLH} = propagation delay time, low-to-high-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡]All typical values are at V_{CC} = 5 V, T_{A} = 25°C. § Not more than one output should be shorted at a time.

NOTE 2: ICC is measured with the inputs grounded and the outputs open.

tpHL = propagation delay time, high-to-low-level output

recommended operating conditions

			18	154LS2!	9B				
			MIN	NOM	MAX.	SN	174LS29	59B	UNIT
Vcc	Supply voltage		4.5	5	5.5	MIN	NOM	MAX	CIVIT
VIH	High-level input voltage		2			4.75	5	5,25	V
VIL	Low-level input voltage		<u> </u>		0.7	2			٧
ГОН	High-level output current	-			- 0.4			8.0	٧
loL	Low-level output current				4			- 0.4	mΑ
		G low	17					. 8	mΑ
tw	Pulse duration	CLR low	10			17			пѕ
		Data before G ↑	20			10			,,,,
t _{su}	Set up time	Address before G1	17	•		20			
		Address before G↓	0			17			ns
		Data after G ↑	0			0			
th	Hold time	Address after G †	0			0			ns
TA	Operating free-air temperature	·	- 55		125	0			
						. 0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54LS259B							
PARAMETER	LEST COMPLITORS.	MIN	TYP	MAX	SN74LS259B			UNIT	
VIK	V _{CC} = MIN, I ₁ = - 18 mA				- 1.5	MIN	TYP	MAX	
	$V_{CC} = MIN$, $V_{1H} = 2V$, $V_{1I} = MAX$,							- 1.5	٧
∨он	IOH = - 0.4 mA		2,5	3,4		2.7	3.4		٧
V	V _{CC} = MIN, V _{IH} = 2 V,	IOL = 4 mA		0,25	0,4		0.05	0.4	
VOL	VII = MAX	IOL = 8 mA					0.25	0.4	V
l ₁	V _{CC} = MAX, V _I = 7 V	-			0.1		0,35	0.5	
ΊΗ	V _{CC} = MAX, V _I = 2.7 V	• • •			20			0,1	mA
	V _{CC} = MAX, V ₁ = 0.4 V				- 0.4			20	μΑ
IIL.								-0.4	mΑ
los§_	V _{CC} = MAX		– 20		- 1 0 0	- 20		100	mΑ
Icc	V _{CC} = MAX, See Note 2			27	36		22	36	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions ‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{ C}$.

NOTE 2: I_{CC} is measured with the inputs grounded and the outputs open.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{C}$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		TEST CONDITIONS		MIN	TYP	MAX	TINU
tPHL .	CLR	Апу О				12	18	ns		
tPLH .	Data	Any Q				19	30	-		
^t PHL	Address Any Q	7617 3	C _L = 15 pF,	$R_L = 2 k\Omega$,		13	20	ns		
tPLH		Anv Ω	Q See Note 3	,		17	27	пş		
tPHL .						14	20			
tPLH .	G	Any Q				15	24			
^t ₽HL	J	,, G				15	24	ns		

 $tp_{LH} = propagation delay time, low-to-high-level output$

tpHL = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[§]Not more than one output should be shorted at a time, and duration short-circuit should not exceed one section.

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated